

A Novel Variation-Aware Low-Power Keeper Architecture for Wide Fan-in Dynamic Gates

ECE 225
Lecture 15

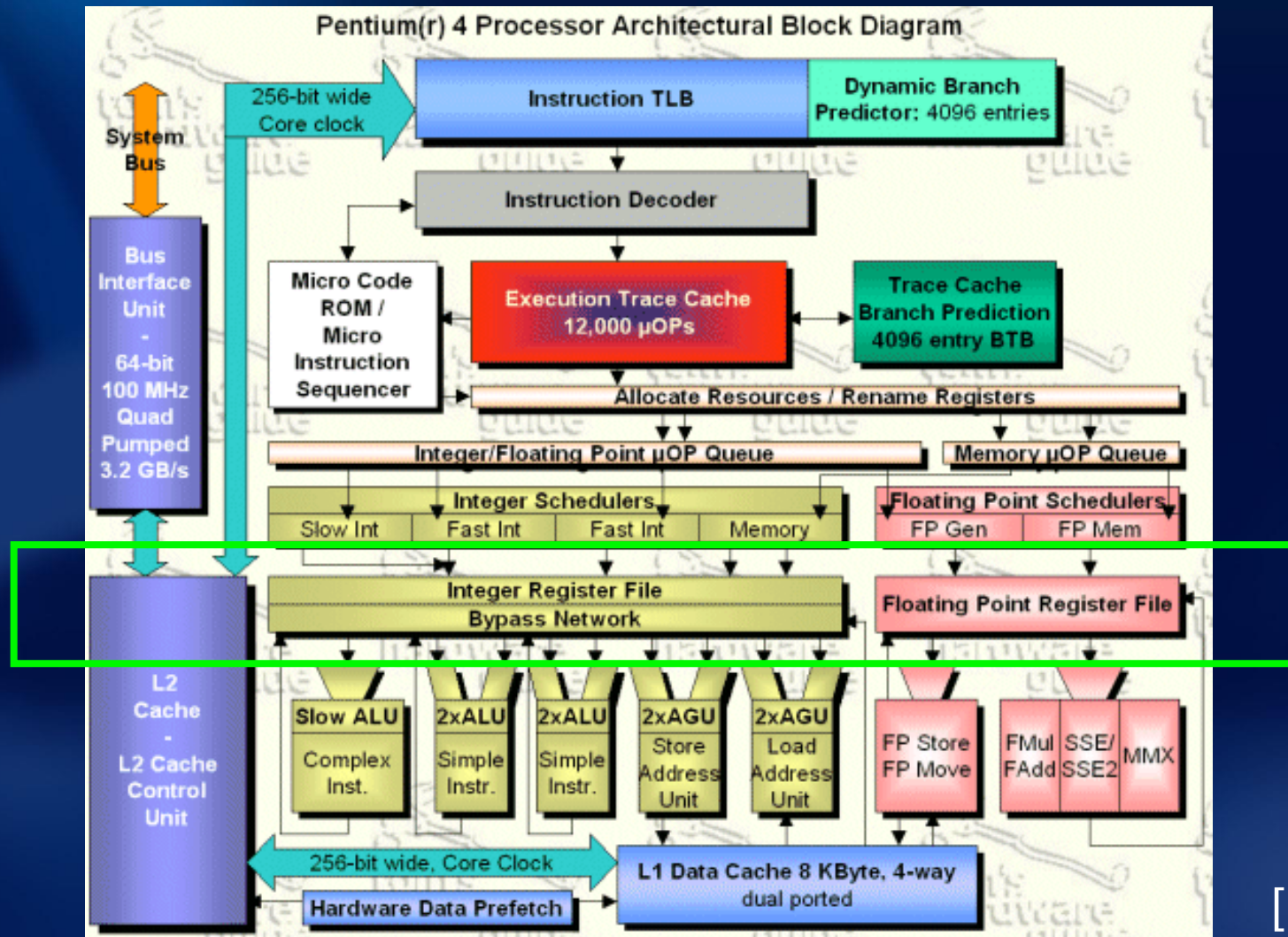
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Outline

- Motivation
- Introduction
- Process Variation
- Keeper Sizing
- Proposed Keeper
- Implementation and Results
- Conclusions

Motivation



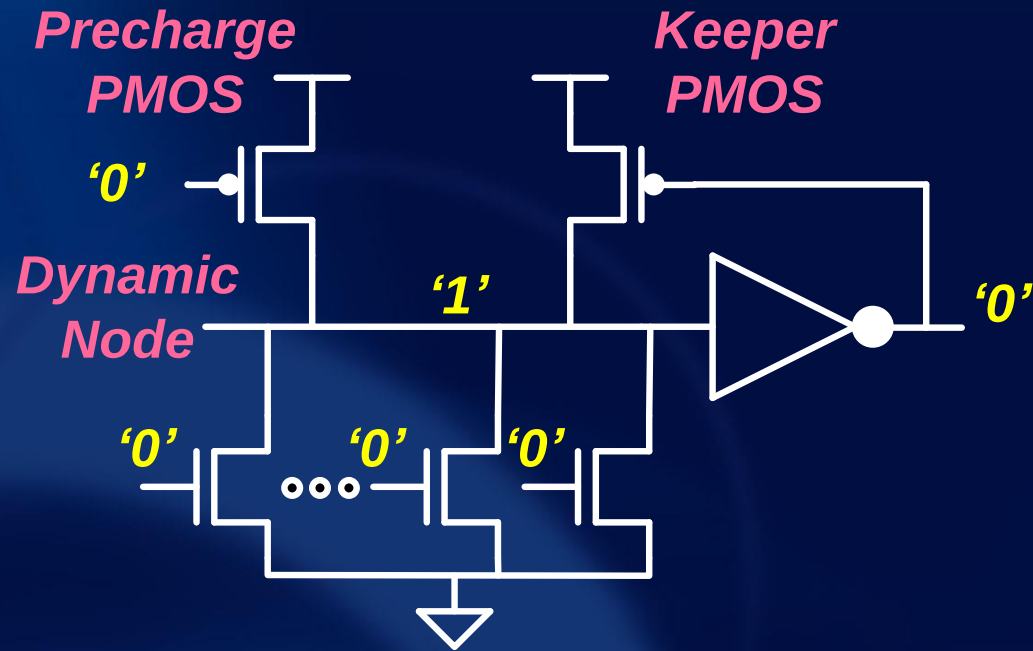
[Intel Inc.]

- Register files are critical modules in computer architecture

Motivation

- Register files are one of the most important components of modern micro-processors.
- Since dynamic gates offer high performance, register files are realized using this type of gate style.
- Wide-Fan-In dynamic OR gates are widely employed in different parts of a register file, such as address decoder and multiplexers.
- Improving performance of wide-Fan-In dynamic OR can significantly improve performance of register files and micro-processors consequently.

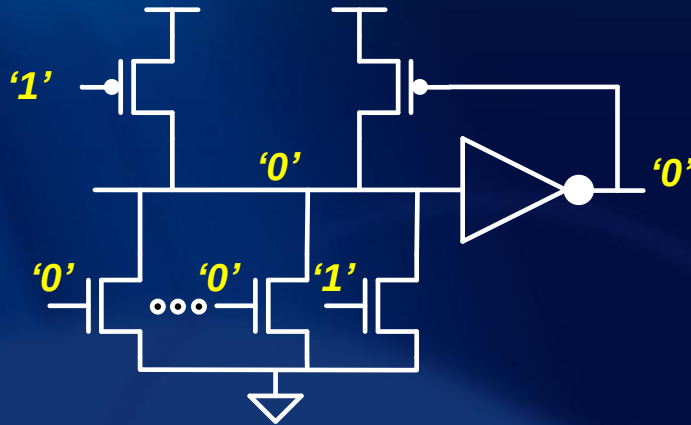
Introduction



Precharge Phase

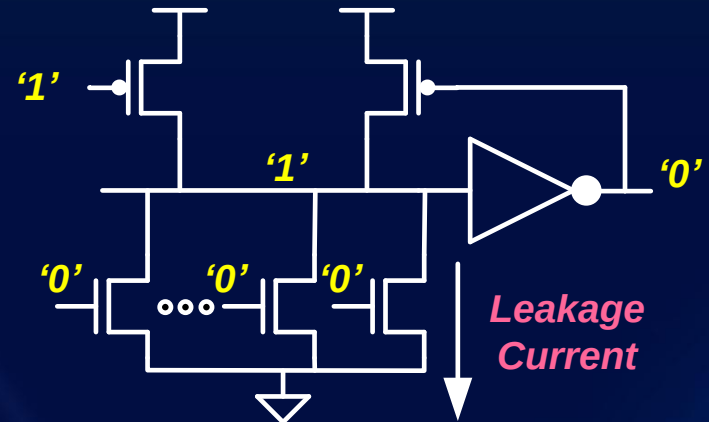
- Pre-charge phase for a wide dynamic OR gate

Introduction



(a) Evaluation Phase :

Larger keeper makes it tougher for NMOS to pull down the dynamic node.

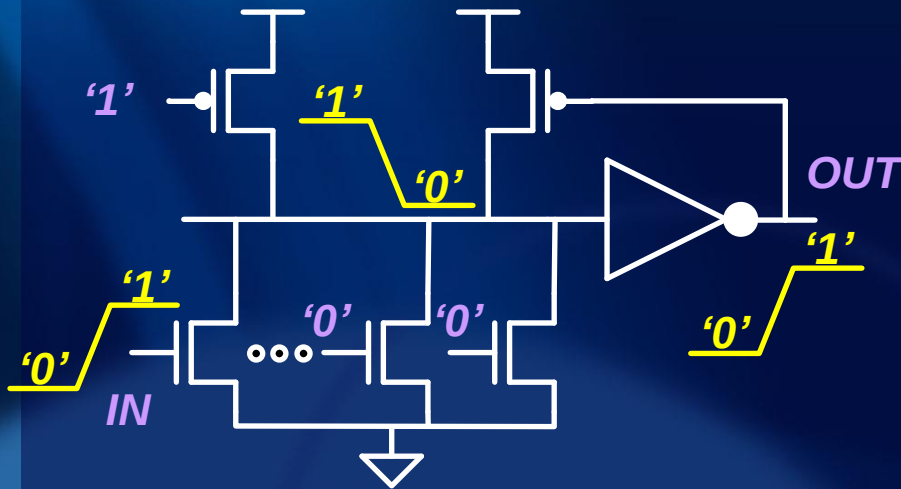


(b) Evaluation Phase :

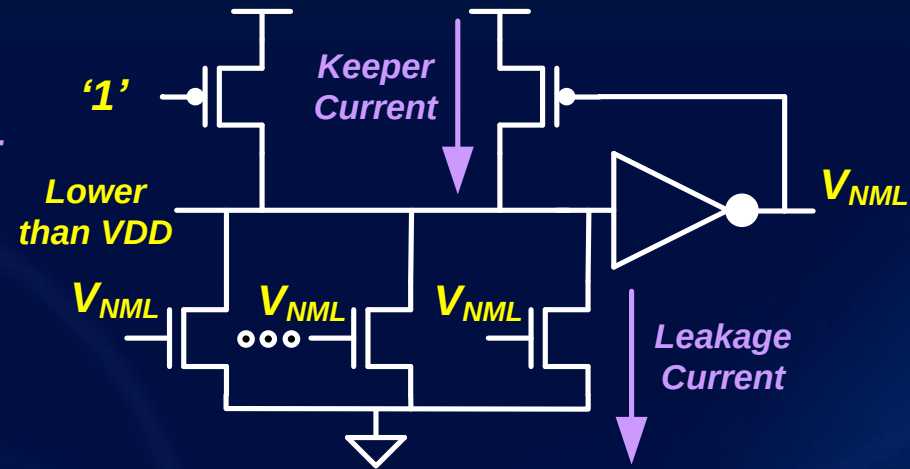
Larger keeper is required to maintain the high voltage of the dynamic node.

- Trade-off between performance and robustness.
- Delay is calculated when only one input is high.
- Noise margin, on the other hand, is measured when all inputs are low.

Introduction



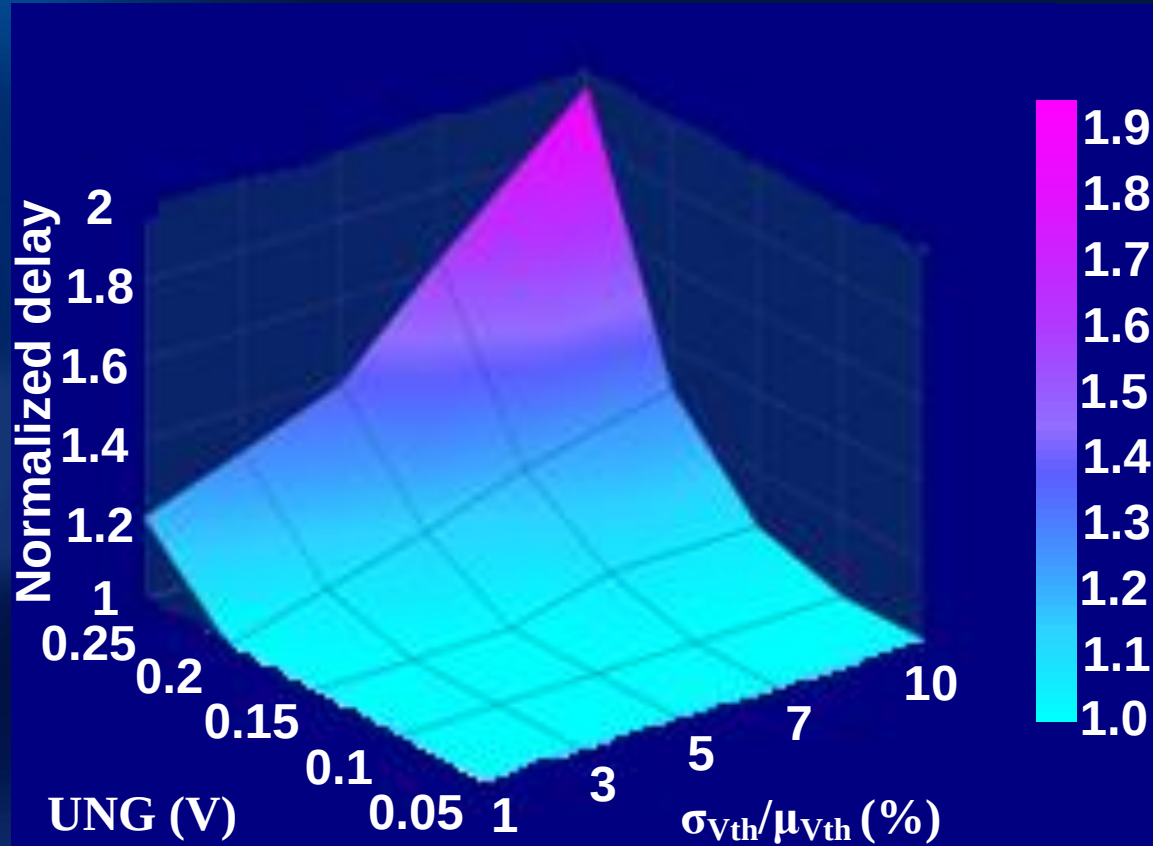
Delay of dynamic gate



Noise margin (Unity Noise Gain)

- Worst case delay is measured when only one input switches (delay from IN to OUT node).
- Noise margin is measured in Unity Gain Margin (UNG) that is the voltage level that when applied to all inputs, results in equal output node voltage.

Introduction

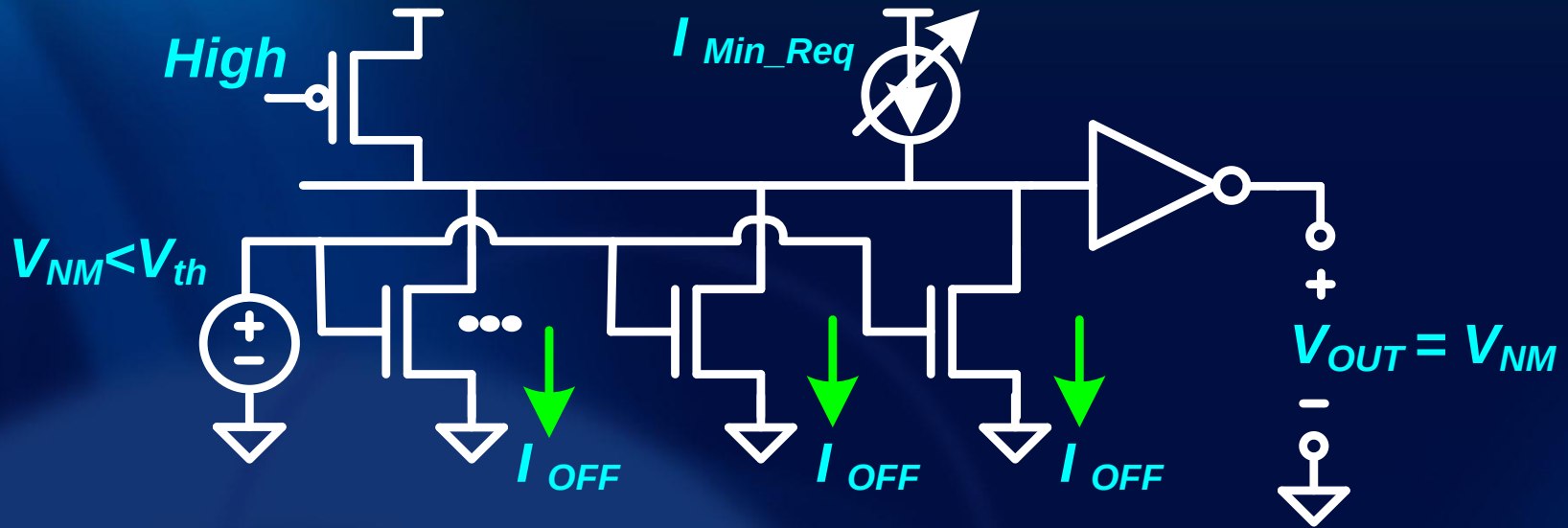


- Graphical presentation of trade-off between delay and noise margin of a wide dynamic OR gate under process variation.

Process Variation

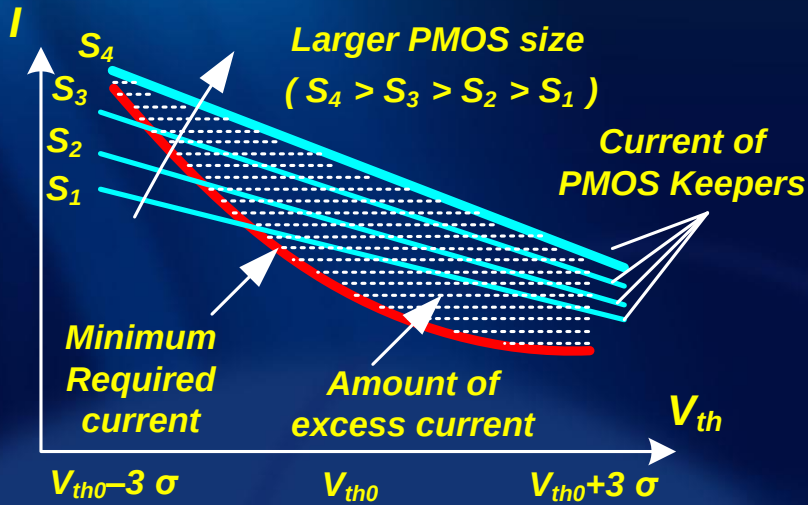
- In this work we focus on correlated variation of threshold voltage; it means that we assume V_{th} of all transistors in a single dynamic gate are altered in same way.
- Impact of random variation can be considered by targeting an appropriate higher design margins.

Keeper Sizing

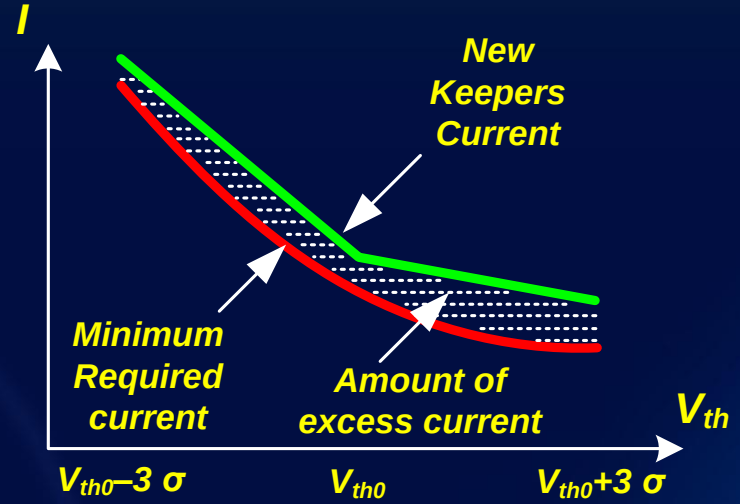


- Minimum required current: Is defined as smallest amount of current that must be injected to dynamic node to guarantee an specified level of UNG.
- Minimum required current will vary as process variation changes V_{th} of pull down network transistors.
- Circuit configuration for measuring UNG under process variation is shown here.

Keeper Sizing



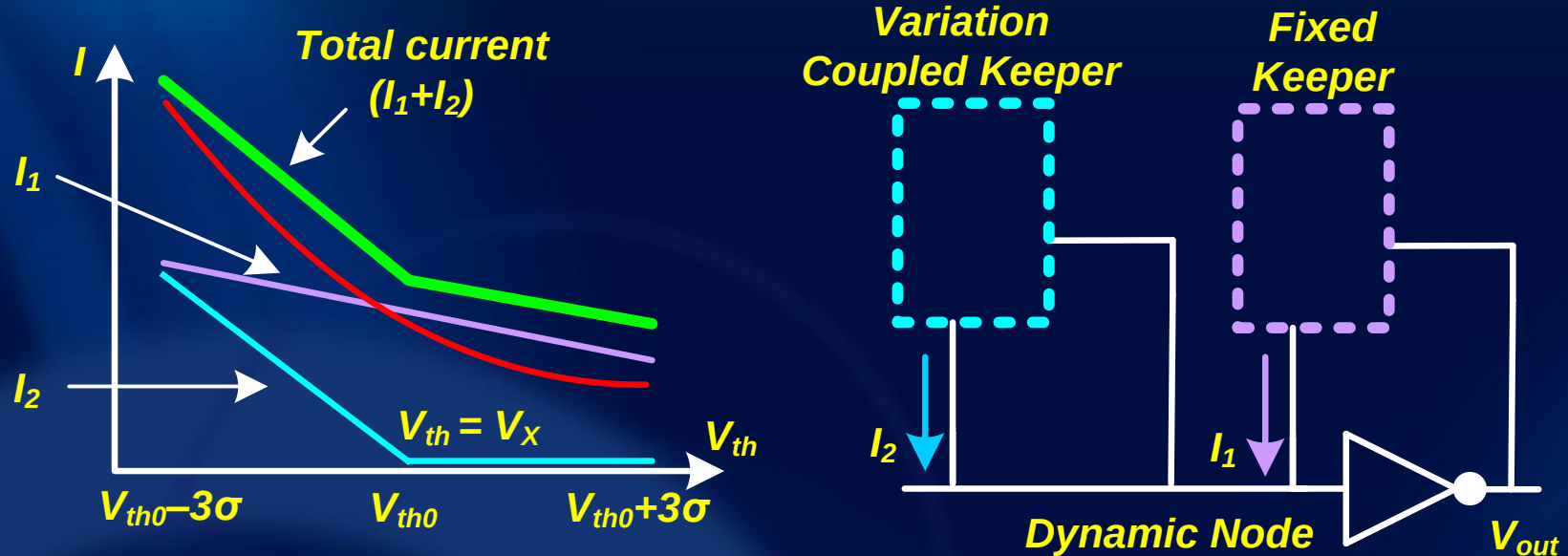
(a) Traditional keeper's behavior



(b) Proposed keeper's behavior

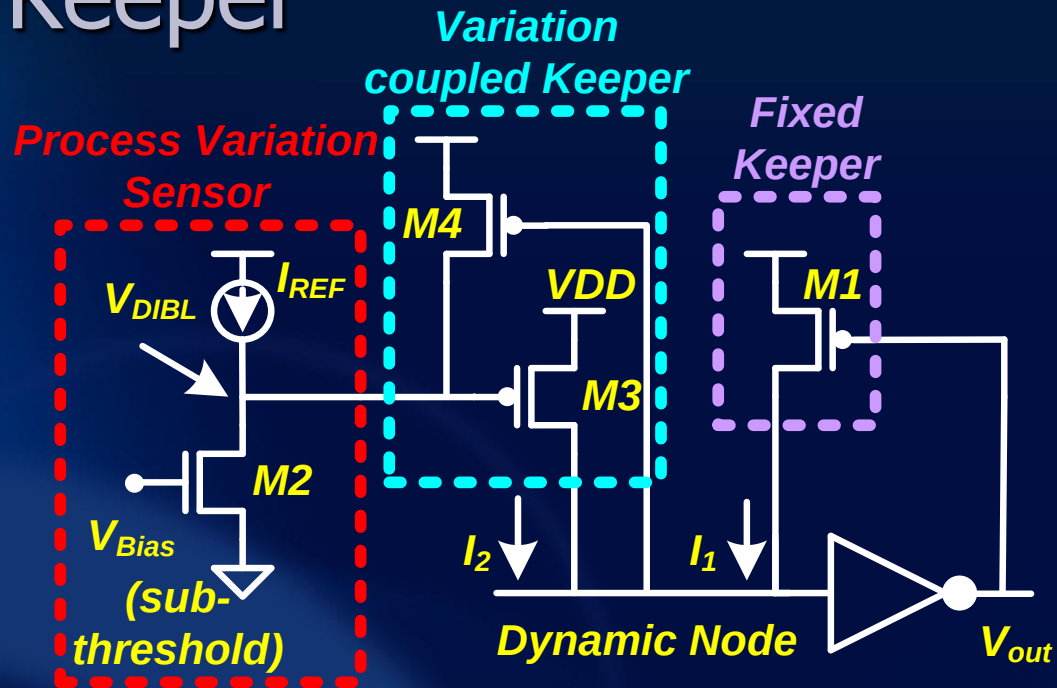
- To maintain the minimum required current level over entire variation range, traditional PMOS keeper must be resized.
- At lower threshold voltage, top line (S_4) supplies enough current; however, at higher threshold voltage huge amount of excess current is injected to node.

Proposed Keeper



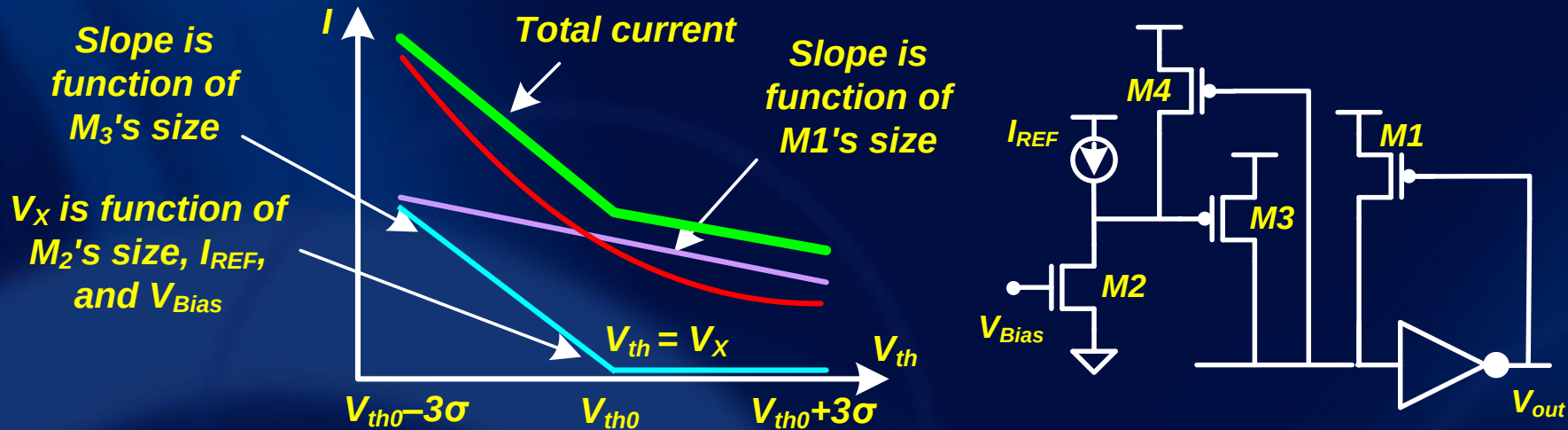
- New keeper is composed of two circuits.
- First one is a small fixed-size PMOS keeper.
- Second one is a variation-coupled keeper.
- Total current shows much better behavior compared to traditional PMOS keepers.

Proposed Keeper



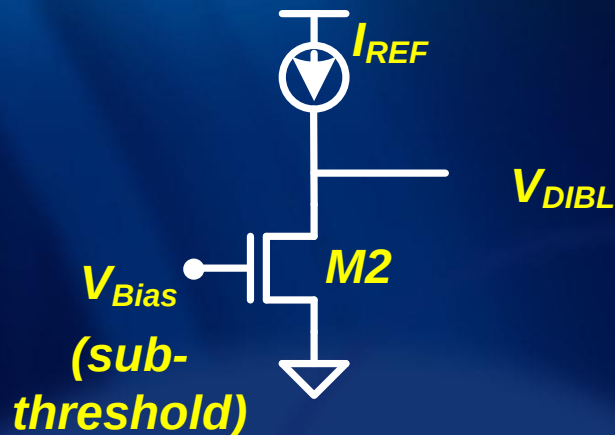
- Beside two keepers, there is a process variation sensor.
- On lower V_{th} side, variation sensor provides higher V_{DIBL} voltage and hence, M_3 supplies less current. On higher V_{th} side vice versa.
- $M4$ is used to turn off $M3$ keeper when dynamic node needs to be pulled down.

Proposed Keeper



- Through analytical equations, circuit parameter affecting keeper current curves have been studied.
- It is shown that each circuit parameter affects a separate part of curves which gives more flexibility in adjusting current curves to get best possible results.

Proposed Keeper



Process Variation Sensor
(Kuroda et al. ISSCC 1996)

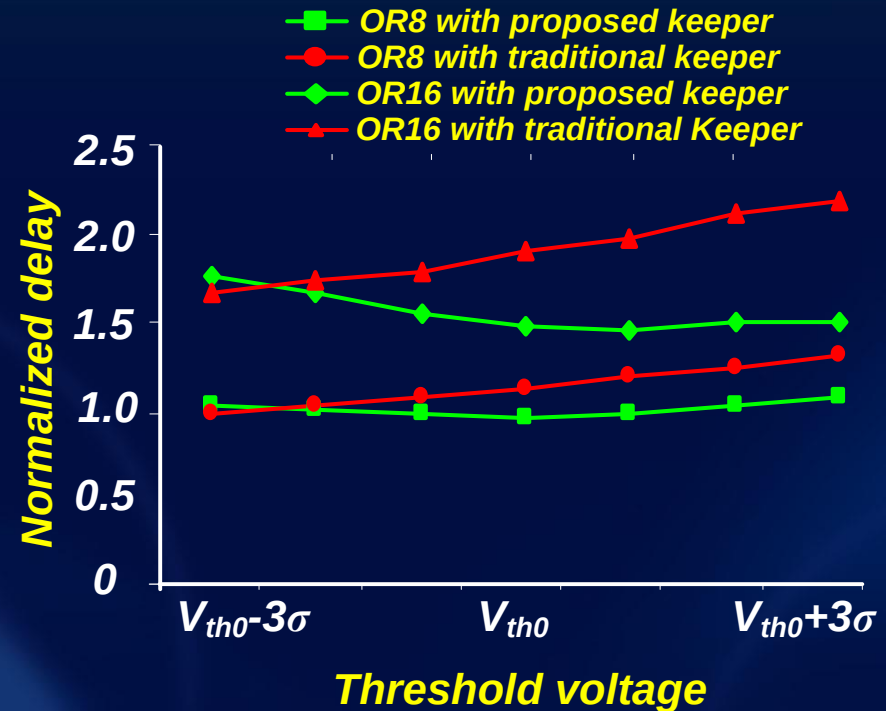
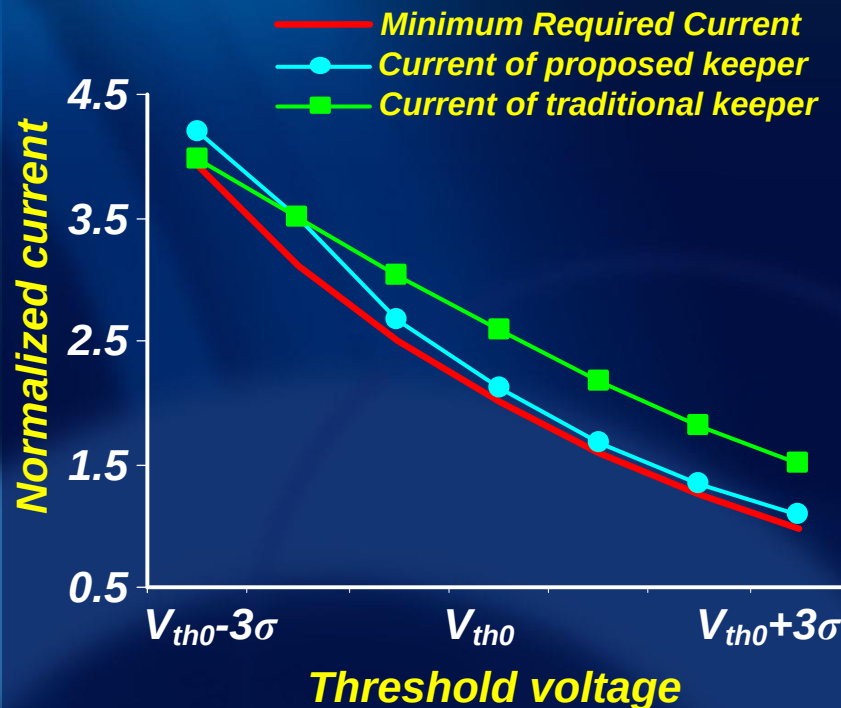
$$(a) \quad I_{REF} = \mu_n C_{ox} \frac{W}{L} V_T^2 e^{\frac{V_{Bias} - (V_{th} - \eta V_{DIBL})}{nV_T}}$$

(b) I_{REF} and V_{Bias} are function of nV_T .

$$(c) \quad V_{th} - \eta V_{DIBL} = cons.$$

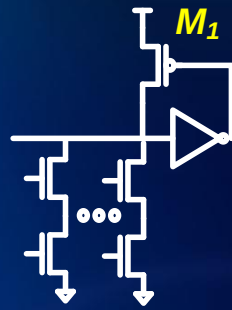
- I_{REF} and V_{Bias} are designed to be independent of V_{th} and its variations.
- M_2 is biased to operate in sub-threshold region.
- Small variation in V_{th} of M_2 causes η time wider fluctuation on V_{DIBL} . (η is DIBL constant).

Implementation and Results

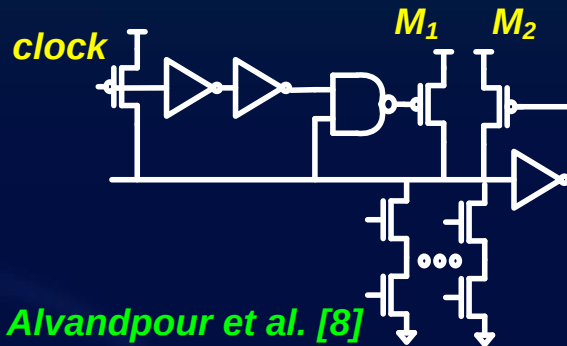


- Normalized current supplied by traditional and proposed keeper vs minimum required current. (left)
- Normalized delay of 8- and 16-input OR gates with traditional and proposed keeper. (right)

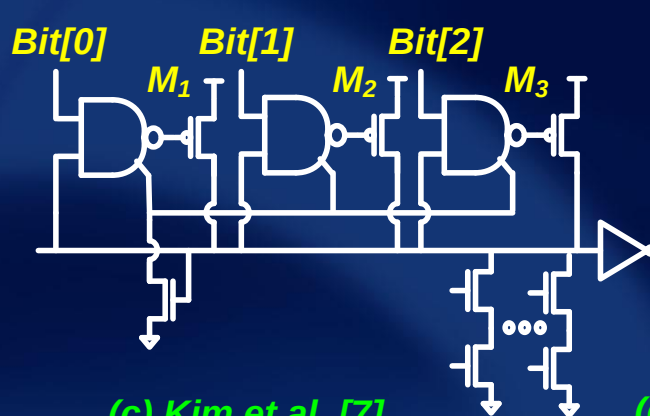
Proposed Keeper



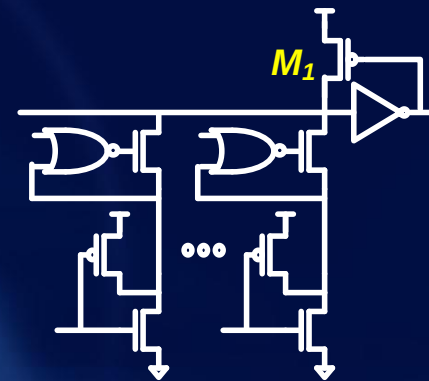
(a) Traditional Keeper



(b) Alvandpour et al. [8]



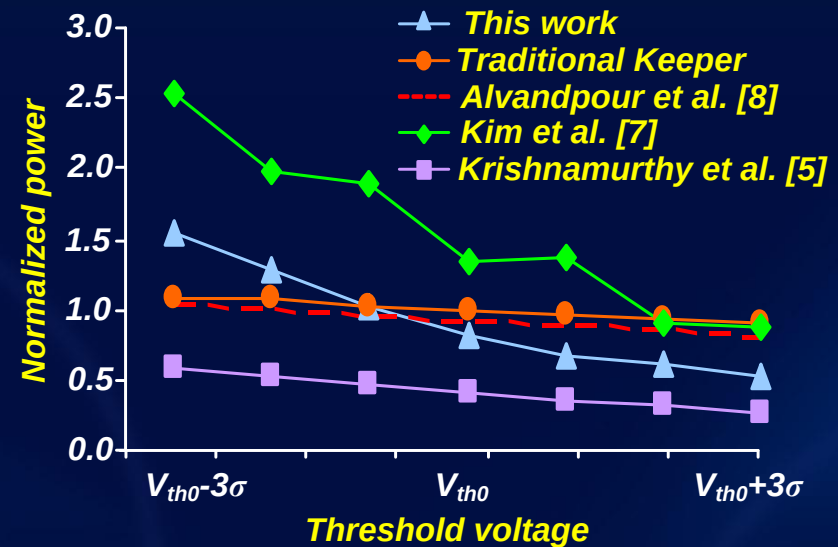
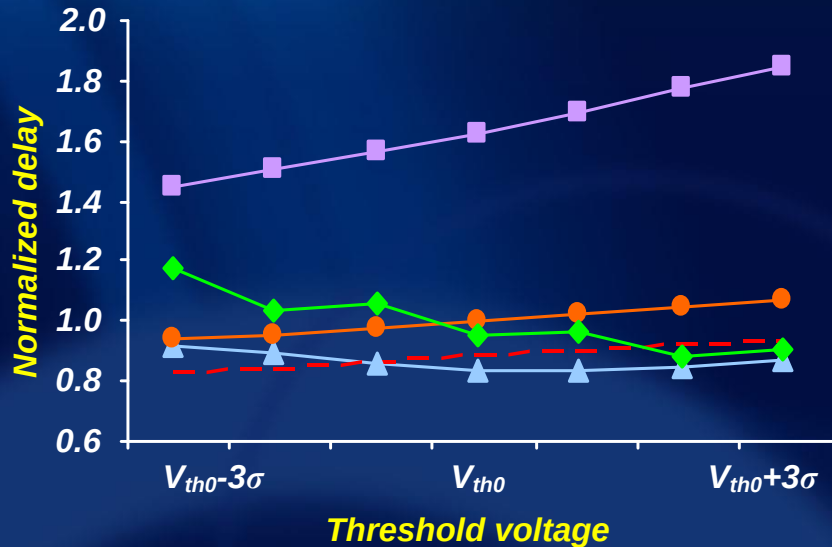
(c) Kim et al. [7]



(d) Krishnamurthy et al. [5]

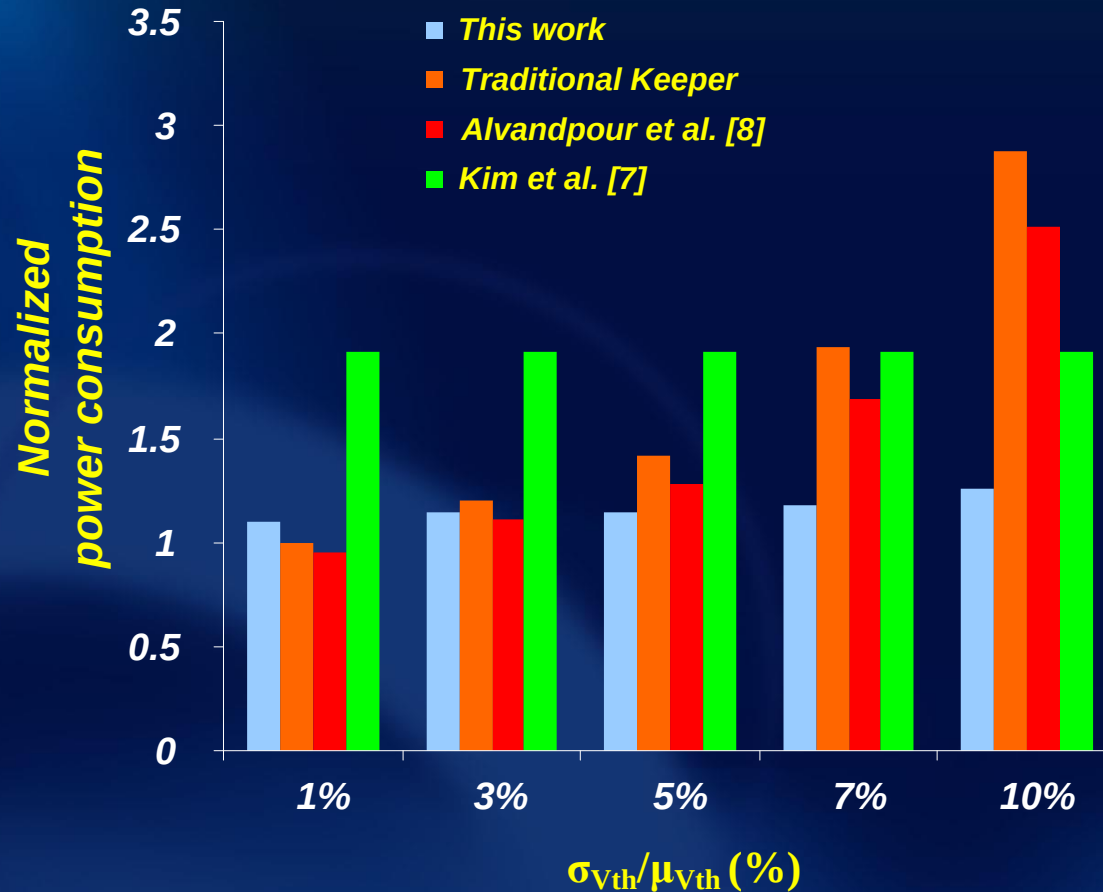
- Proposed keeper has been compared to previous work.
- Mean delay value, power consumption and standard deviation of delay are used as metrics.

Implementation and Results



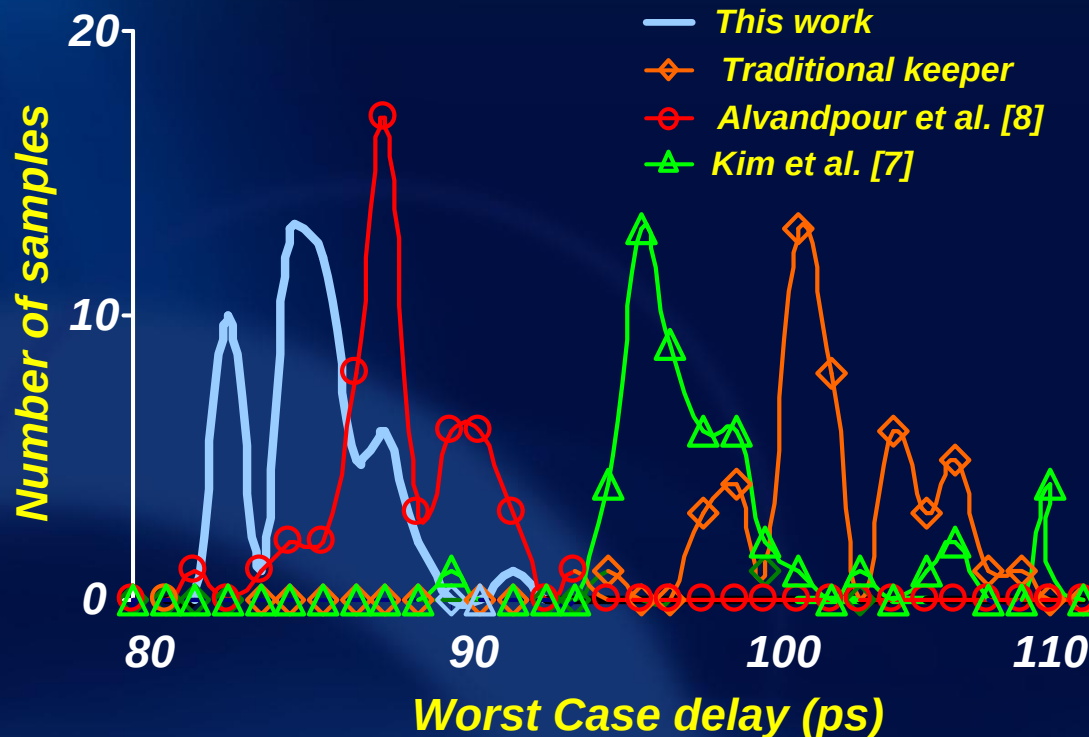
- Comparison between normalized mean delay (left) and power consumption (right) of OR gates realized by different keepers.
- Proposed keeper shows low delay and power consumption.

Implementation and Results



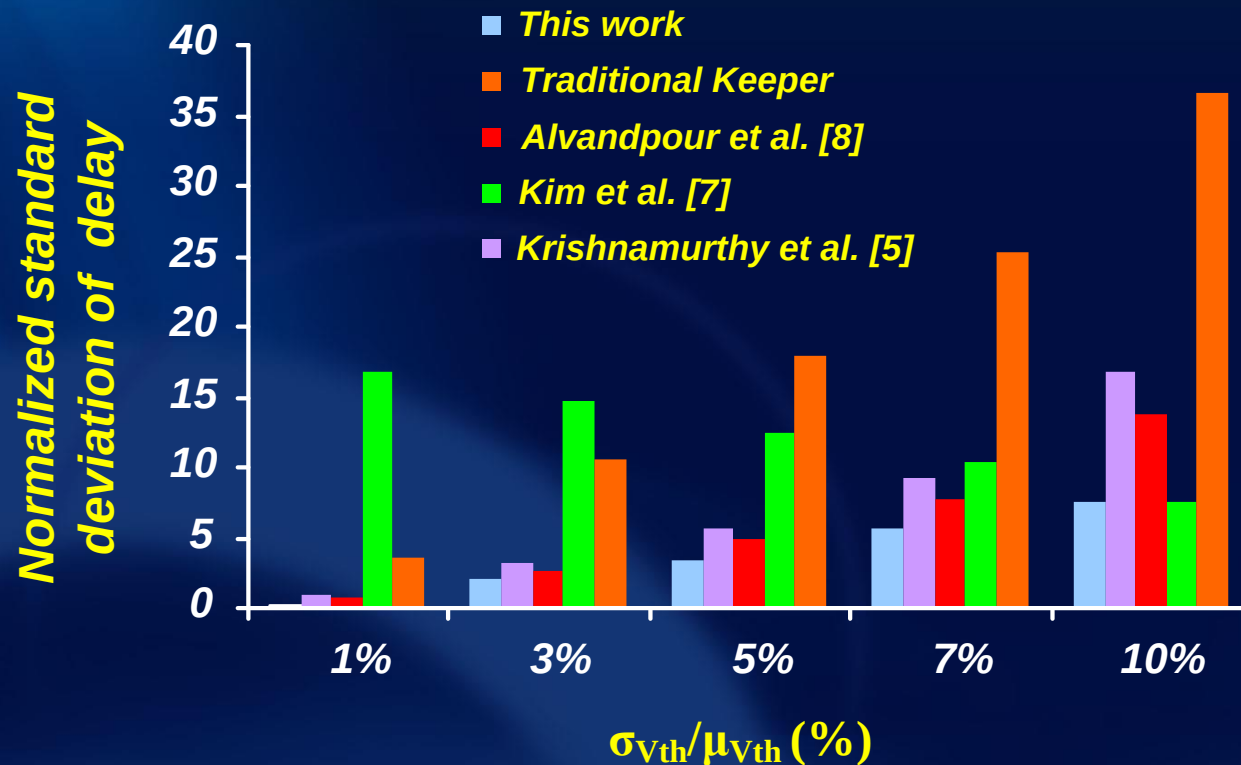
- Normalized power consumption for different keepers at different levels of process variation ($\sigma_{V_{th}}/\mu_{V_{th}}$).

Implementation and Results



- Delay distribution of dynamic OR gates with different keeper circuits obtained for 100 samples.
- Distribution corresponded to proposed keeper shows lower mean and narrower spread.

Implementation and Results



- Normalized STD of delay for different keepers at different levels of process variation ($\sigma_{V_{th}}/\mu_{V_{th}}$).
- Proposed keeper shows superior behavior in terms of robustness to increasing level of variation.

Conclusions

- A novel approach for designing low-power variation-aware keeper circuits of wide fan-in dynamic gates has been presented.
- Through a graphical representation, it was shown that conventional keeper circuits generate unnecessary excess contention that can be avoided with proper design of keeper.
- HSPICE simulation results show that the proposed architecture offers smallest delay deviation for entire V_{th} range considered in this study, compared to all existing works in the literature.
- The proposed keeper architecture could be very effective in increasing the robustness of dynamic gates to process variation.